



MS RCE
PATENT
8053-1008

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of: Yuichi NAITOU et al.
Conf.: 7712
Appl. No.: 09/981,390
Group: 2881
Filed: October 18, 2001
Examiner: Phillip Johnston
Title: SCANNING PROBE MICROSCOPE WITH PROBE
FORMED BY SINGLE CONDUCTIVE MATERIAL

AMENDMENT

Assistant Commissioner for Patents
Alexandria, VA 22313-1450

December 5, 2003

Sir:

In response to the Office Action mailed August 5, 2003,
please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing
of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 21 of this paper.

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